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APPLICATION NO.	FILING DATE		FIRST NAMED INVENTOR	ATTORNEY DOCKET NO.	CONFIRMATION NO.		
10/750,470	1:	2/31/2003	Hyo-Cheon Kang	2522-041	9867		
20575	7590	11/16/2004		EXAM	EXAMINER		
MARGER J 1030 SW MC		N & MCCOLLON STREET	LEE, C	LEE, CALVIN			
PORTLAND, OR 97205				ART UNIT	PAPER NUMBER		
				2025			

DATE MAILED: 11/16/2004

Please find below and/or attached an Office communication concerning this application or proceeding.

			M/			
	Application No.	Applicant(s)				
	10/750,470	KANG, HYO-CHEON	I			
Office Action Summary	Examiner	Art Unit				
	Lee, Calvin	2825				
The MAILING DATE of this communication appears on the cover sheet with the correspondence address						
Period for Reply A SHORTENED STATUTORY PERIOD FOR REPLY	/ IS SET TO EXPIRE 1 MG	ONTH(S) FROM				
THE MAILING DATE OF THIS COMMUNICATION. - Extensions of time may be available under the provisions of 37 CFR 1.13 after SIX (6) MONTHS from the mailing date of this communication. - If the period for reply specified above is less than thirty (30) days, a reply if NO period for reply is specified above, the maximum statutory period was really reply received by the Office later than three months after the mailing earned patent term adjustment. See 37 CFR 1.704(b).	36(a). In no event, however, may a re within the statutory minimum of thirty will apply and will expire SIX (6) MON cause the application to become AB.	eply be timely filed y (30) days will be considered timely. THS from the mailing date of this comm ANDONED (35 U.S.C. § 133).	nunication.			
Status						
1) Responsive to communication(s) filed on						
<i>,</i>	action is non-final.					
3) Since this application is in condition for allowar			ierits is			
closed in accordance with the practice under E	x parte Quayle, 1935 C.D.	. 11, 453 O.G. 213.				
Disposition of Claims						
4) Claim(s) 1-25 is/are pending in the application.						
4a) Of the above claim(s) is/are withdraw	vn from consideration.					
5) Claim(s) is/are allowed.						
6) Claim(s) is/are rejected.						
7) Claim(s) is/are objected to. 8) ☑ Claim(s) <u>1-25</u> are subject to restriction and/or election requirement.						
O/ Ordini(s) 1-25 are subject to restriction and/or e	sicotion requirement.					
Application Papers						
9) The specification is objected to by the Examine		_				
10) The drawing(s) filed on is/are: a) acce						
Applicant may not request that any objection to the Replacement drawing sheet(s) including the correct			1 121/4\			
11) The oath or declaration is objected to by the Ex	•					
,						
Priority under 35 U.S.C. § 119						
12) Acknowledgment is made of a claim for foreign	priority under 35 U.S.C. §	119(a)-(d) or (f).				
a) All b) Some * c) None of:						
 1. Certified copies of the priority documents have been received. 2. Certified copies of the priority documents have been received in Application No 						
3. Copies of the certified copies of the priority documents have been received in this National Stage						
application from the International Bureau (PCT Rule 17.2(a)).						
* See the attached detailed Office action for a list of the certified copies not received.						
Attachment(s)	A) [] Interview C	ummary (PTO-413)				
 Notice of References Cited (PTO-892) Notice of Draftsperson's Patent Drawing Review (PTO-948) 	Paper No(s	s)/Mail Date				
3) Information Disclosure Statement(s) (PTO-1449 or PTO/SB/08) Paper No(s)/Mail Date	5) Notice of In 6) Other:	nformal Patent Application (PTO-15 	52)			

Page 2

Application No: 10/750,470

Docket No: 2522-041

Hyo-Cheon KANG

OFFICE ACTION

Election/Restriction

1. Claims 1-23 are pending in this application.

Restriction to one of the following inventions is required under 35 U.S.C. 121:

- (A) Claims 1-18 and 23-25, drawn to a method for inspecting a wafer, classified in class 250, subclass 310;
- (B) Claims 19-22, drawn to an apparatus for inspecting a wafer, classified in class 324, subclass 750
- 2. Inventions (claims 1-18 and 23-25) and (claims 19-22) are related as process and apparatus for its practice. The inventions are distinct if it can be shown that either: (1) the process as claimed can be practiced by another materially different apparatus or by hand, or (2) the apparatus as claimed can be used to practice another and materially different process. (MPEP § 806.05(e)).

In this case: (Group B compared to Group A) the defect analyzing means for detecting a defect of a wafer, in an inspecting apparatus, can be detected not only by analyzing a signal generated from a signal processing means (which is found in Group A and B), but also by analyzing or comparing reflecting signal(s) to an ideal (or standard) signal, by analyzing voltage and/or current generated by a signal beaming, and by many other techniques (which is silent in Group A).

3. Applicant is advised that the reply to this requirement to be completed must include an election of the invention to be examined even though the requirement is traversed (37CFR 1.143)

Contact Information

4. Any inquiry concerning this communication from the Examiner should be directed to *Calvin Lee* at (571) 272-1896 from 7:00AM to 5:00PM (Monday-Thursday, Eastern Time). If attempts to reach the examiner by telephone are unsuccessful, Art Unit 2825's Supervisory Patent Examiner *Matthew Smith* can be reached at (571) 272-1907.

Any inquiry relating to the status of this application should be directed to the Group receptionist whose telephone number is (703) 308-0596. The central fax number is (703) 872-9306 for all communications to be entered (e.g., amendments, remarks, IDS, etc.)

November 12, 2004

calomle